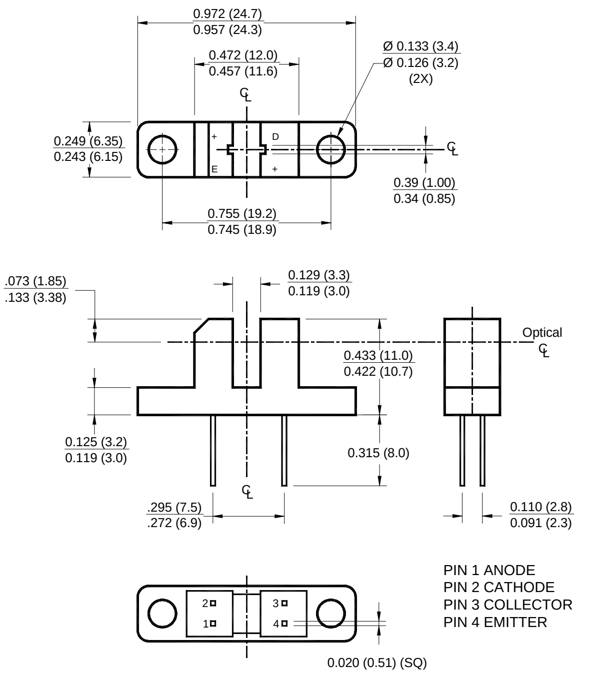
H21A1 / H21A2 / H21A3
PHOTOTRANSISTOR
OPTICAL INTERRUPTER SWITCH

PACKAGE DIMENSIONS

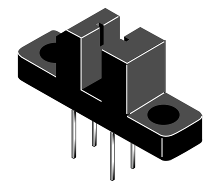


NOTES:

1. Dimensions for all drawings are in inches (mm).
2. Tolerance of ± .010 (.25) on all non-nominal dimensions unless otherwise specified.

DESCRIPTION

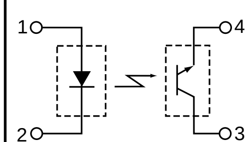
The H21A1, H21A2 and H21A3 consist of a gallium arsenide infrared emitting diode coupled with a silicon phototransistor in a plastic housing. The packaging system is designed to optimize the mechanical resolution, coupling efficiency, ambient light rejection, cost and reliability. The gap in the housing provides a means of interrupting the signal with an opaque material, switching the output from an “ON” to an “OFF” state.



FEATURES

- Opaque housing
- Low cost
- .035” apertures
- High $I_{C(ON)}$

SCHEMATIC



1. Derate power dissipation linearly 1.33 mW/°C above 25°C.
2. RMA flux is recommended.
3. Methanol or isopropyl alcohols are recommended as cleaning agents.
4. Soldering iron tip 1/16” (1.6mm) minimum from housing.

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C unless otherwise specified)

Parameter	Symbol	Rating	Unit
Operating Temperature	T_{OPR}	-55 to +100	°C
Storage Temperature	T_{STG}	-55 to +100	°C
Soldering Temperature (Iron)(2,3 and 4)	T_{SOL-I}	240 for 5 sec	°C
Soldering Temperature (Flow)(2 and 3)	T_{SOL-F}	260 for 10 sec	°C
INPUT (EMITTER)			
Continuous Forward Current	I_F	50	mA
Reverse Voltage	V_R	6	V
Power Dissipation (1)	P_D	100	mW
OUTPUT (SENSOR)			
Collector to Emitter Voltage	V_{CEO}	30	V
Emitter to Collector Voltage	V_{ECO}	4.5	V
Collector Current	I_C	20	mA
Power Dissipation (T_C = 25°C)(1)	P_D	150	mW

ELECTRICAL / OPTICAL CHARACTERISTICS (T_A =25°C)(All measurements made under pulse condition)

PARAMETER	TEST CONDITIONS	SYMBOL	DEVICES	MIN	TYP	MAX	UNITS
INPUT (EMITTER) Forward Voltage	I_F = 60 mA	V_F	All	—	—	1.7	V
Reverse Breakdown Voltage	I_R = 10 µA	V_R	All	6.0	—	—	V
Reverse Leakage Current	V_R = 3 V	I_R	All	—	—	1.0	µA
OUTPUT (SENSOR) Emitter to Collector Breakdown	I_F = 100 µA, Ee = 0	BV_{ECO}	All	6.0	—	—	V
Collector to Emitter Breakdown	I_C = 1 mA, Ee = 0	BV_{CEO}	All	30	—	—	V
Collector to Emitter Leakage	V_{CE} = 25 V, Ee = 0	I_{CEO}	All	—	—	100	nA
COUPLED On-State Collector Current	I_F = 5 mA, V_{CE} = 5 V	$I_{C(ON)}$	H21A1	0.15	—	—	mA
			H21A2	0.30	—	—	
			H21A3	0.60	—	—	
	I_F = 20 mA, V_{CE} = 5 V		H21A1	1.0	—	—	
			H21A2	2.0	—	—	
			H21A3	4.0	—	—	
	I_F = 30 mA, V_{CE} = 5 V		H21A1	1.9	—	—	
			H21A2	3.0	—	—	
			H21A3	5.5	—	—	
Saturation Voltage	I_F = 20 mA, I_C = 1.8 mA	$V_{CE(SAT)}$	H21A2/3	—	—	0.40	V
	I_F = 30 mA, I_C = 1.8 mA		H21A1	—	—	0.40	V
Turn-On Time	I_F = 30 mA, V_{CC} = 5 V, R_L = 2.5 KΩ	t_{on}	All	—	8	—	µs
Turn-Off Time	I_F = 30 mA, V_{CC} = 5 V, R_L = 2.5 KΩ	t_{off}	All	—	50	—	µs

Figure 1. Output Current vs. Input Current

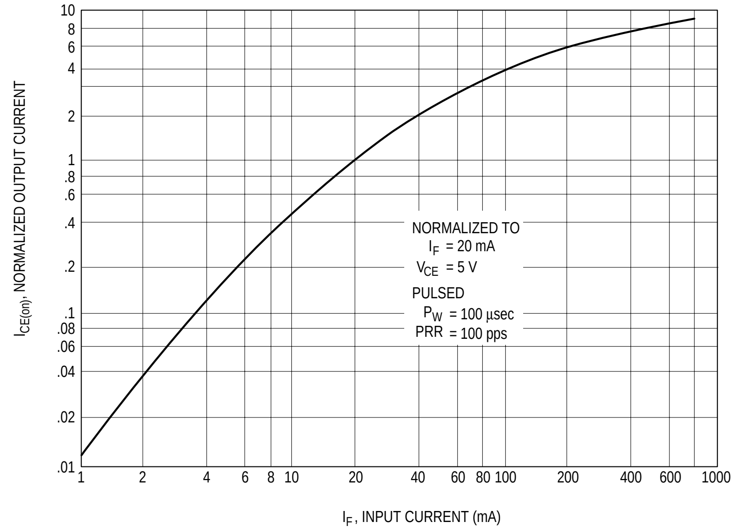


Figure 2. Output Current vs. Temperature

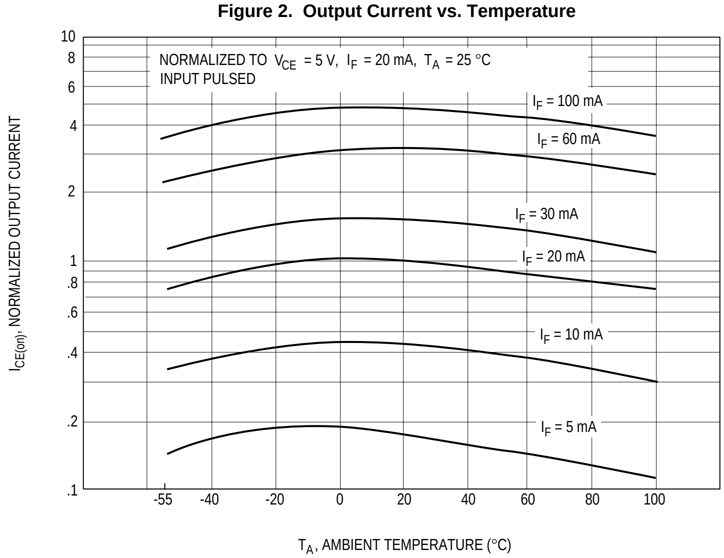


Figure 3. $V_{CE(SAT)}$ vs. Temperature

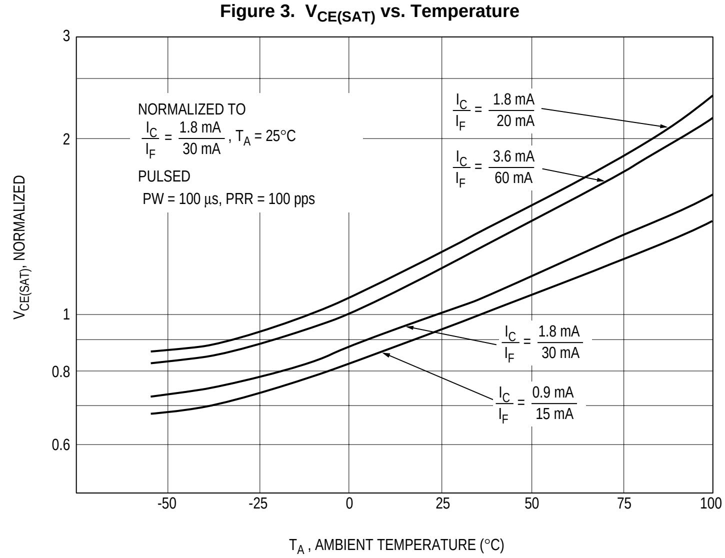


Figure 4. Leakage Current vs. Temperature

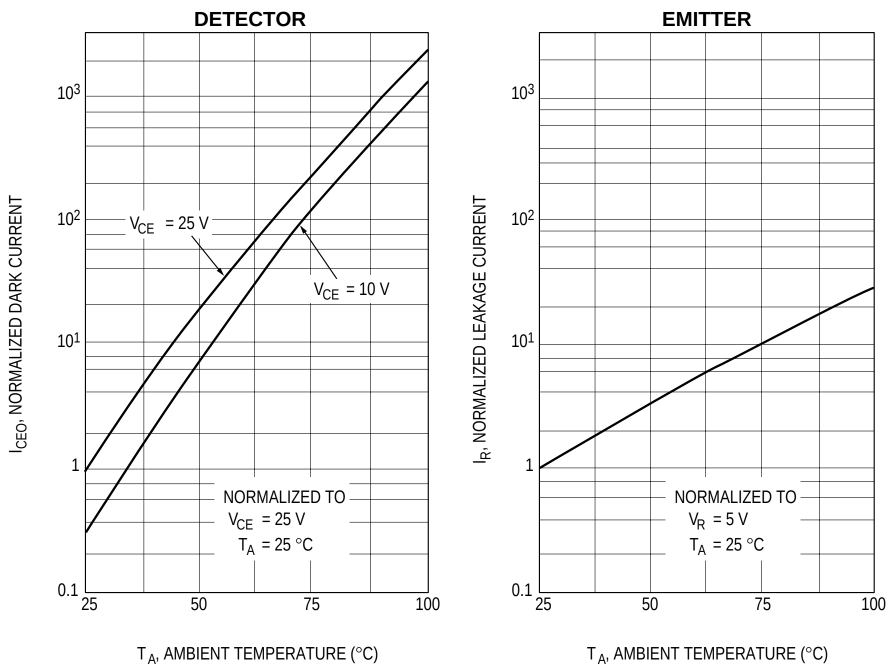


Figure 5. Switching Speed vs. RL

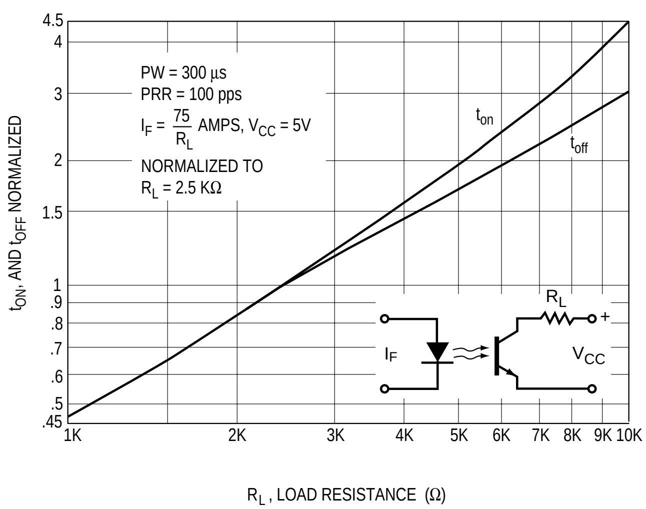
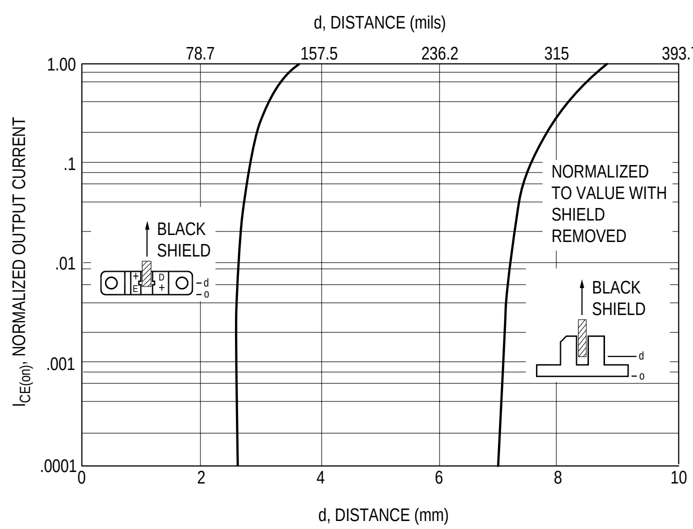


Figure 6. Output Current vs. Distance



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